Infineon Technologies - XMC1402Q064X0200AAXUMA1 Datasheet

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Applications of "Embedded - Microcontrollers"

Details	
Product Status	Active
Core Processor	ARM® Cortex®-M0
Core Size	32-Bit Single-Core
Speed	48MHz
Connectivity	I²C, LINbus, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, I²S, POR, PWM, WDT
Number of I/O	48
Program Memory Size	200KB (200K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	16K x 8
Voltage - Supply (Vcc/Vdd)	1.8V ~ 5.5V
Data Converters	A/D 12x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 105°C (TA)
Mounting Type	Surface Mount
Package / Case	64-VFQFN Exposed Pad
Supplier Device Package	PG-VQFN-64-6
Purchase URL	https://www.e-xfl.com/product-detail/infineon-technologies/xmc1402q064x0200aaxuma1

Features

CPU subsystem

- 32-bit ARM Cortex-M0 CPU Core
  - 0.84 DMIPS/MHz (Dhrystone 2.1) at 48 MHz
- Nested Vectored Interrupt Controller
- 64 interrupt nodes
- MATH coprocessor
  - 24-bit trigonometric calculation (CORDIC)
  - 32-bit divide operation
- 2x4 channels ERU for event interconnections

On-Chip Memories

- 8 Kbyte ROM
- 16 Kbyte SRAM (with parity)
- up to 200 Kbyte Flash (with ECC)

Supply, Reset and Clock

- 1.8 V to 5.5 V supply with power on reset and brownout detector
- On-chip clock monitor
- External crystal oscillator support (32 kHz and 4 to 20 MHz)
- Internal slow and fast oscillators without the need of PLL

System Control

- Window watchdog
- Real time clock module
- Pseudo random number generator

Communication Peripherals

- Four USIC channels, usable as
  - UART (up to 12 Mb/s)
  - single-SPI (up to 12 Mb/s)
  - double-SPI (up to 2 × 12 Mb/s)
  - quad-SPI (up to 4 × 12 Mb/s)
  - IIC (up to 400 kb/s)
  - IIS (up to 12 Mb/s)
  - LIN interfaces (20kb/s)
- LEDTS in Human-Machine interface
  - up to 24 touch pads
  - drive up to 144 LEDs
- MultiCAN+, Full-CAN/Basic-CAN with 2 nodes, 32 message objects (up to 1 MBaud)

Analog Frontend Peripherals

- A/D Converters (up to 12 analog inputs)
  - 2 sample and hold stages
  - fast 12-bit ADC (up to 1.1 MS/s), adjustable gain
  - 0 V to 5.5 V input range
- Up to 8 channels out of range comparators
- Up to 4 fast analog comparators
- Temperature Sensor

Industrial Control Peripherals

- 2x4 16-bit 96 MHz CCU4 timers for signal monitoring and PWM
- 2x4 16-bit 96 MHz CCU8 timers for complex PWM, complementary high/low side switches and multi phase control
- 2x POSIF for hall and quadrature encoders, motor positioning
- 9 channel BCCU (brightness and color control) for LED lighting applications

Up to 56 Input/Output Ports

- 1.8 V to 5.5 V capable
- up to 8 high current pads (50 mA sink)

On-Chip Debug Support

- 4 breakpoints, 2 watchpoints
- ARM serial wire debug, single-pin debug interfaces

Programming Support

- Single-pin bootloader
- Secure bootstrap loader SBSL (optional)

Packages

- TSSOP-38 (9.7 × 6.4 mm^2)
- VQFN-40/48/64 (5×5/7×7/8×8 mm^2)
- LQFP-64 (12 × 12 mm^2)

Tools

- Free DAVE™ toolchain with low level drivers and apps

Table 3 XMC1400 Chip Identification Number (cont'd)

Derivative	Value	Marking
XMC1403-Q064X0200	00014093 07CF00FF 1E071FF7 00B00000 00000D00 00001000 00033000 10204083_H	AA
XMC1404-Q048X0064	00014083 07FF00FF 1E071FF7 30BFF00F 00000D00 00001000 00011000 10204083_H	AA
XMC1404-Q048X0128	00014083 07FF00FF 1E071FF7 30BFF00F 00000D00 00001000 00021000 10204083_H	AA
XMC1404-Q048X0200	00014083 07FF00FF 1E071FF7 30BFF00F 00000D00 00001000 00033000 10204083_H	AA
XMC1404-Q064X0064	00014093 07FF00FF 1E071FF7 30BFF00F 00000D00 00001000 00011000 10204083_H	AA
XMC1404-Q064X0128	00014093 07FF00FF 1E071FF7 30BFF00F 00000D00 00001000 00021000 10204083_H	AA
XMC1404-Q064X0200	00014093 07FF00FF 1E071FF7 30BFF00F 00000D00 00001000 00033000 10204083_H	AA
XMC1404-F064X0064	000140A3 07FF00FF 1E071FF7 30BFF00F 00000D00 00001000 00011000 10204083_H	AA
XMC1404-F064X0128	000140A3 07FF00FF 1E071FF7 30BFF00F 00000D00 00001000 00021000 10204083_H	AA
XMC1404-F064X0200	000140A3 07FF00FF 1E071FF7 30BFF00F 00000D00 00001000 00033000 10204083_H	AA

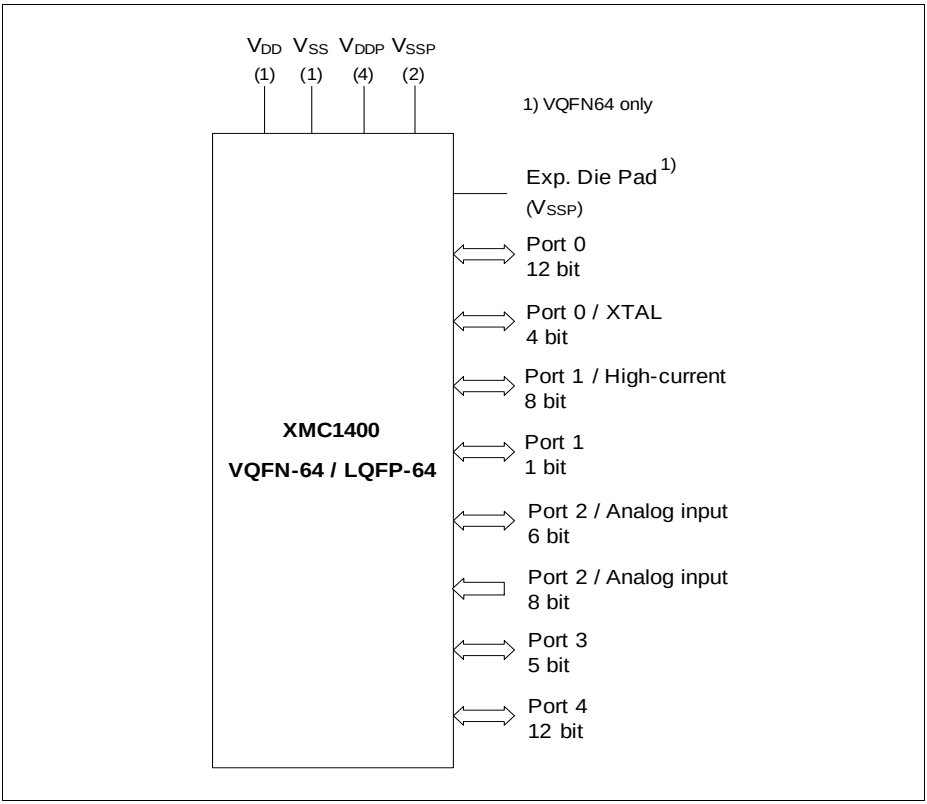


Figure 5 XMC1400 Logic Symbol for PG-LQFP-64-26 / PG-VQFN-64-6

2.2 Pin Configuration and Definition

The following figures summarize all pins, showing their locations on the different packages.

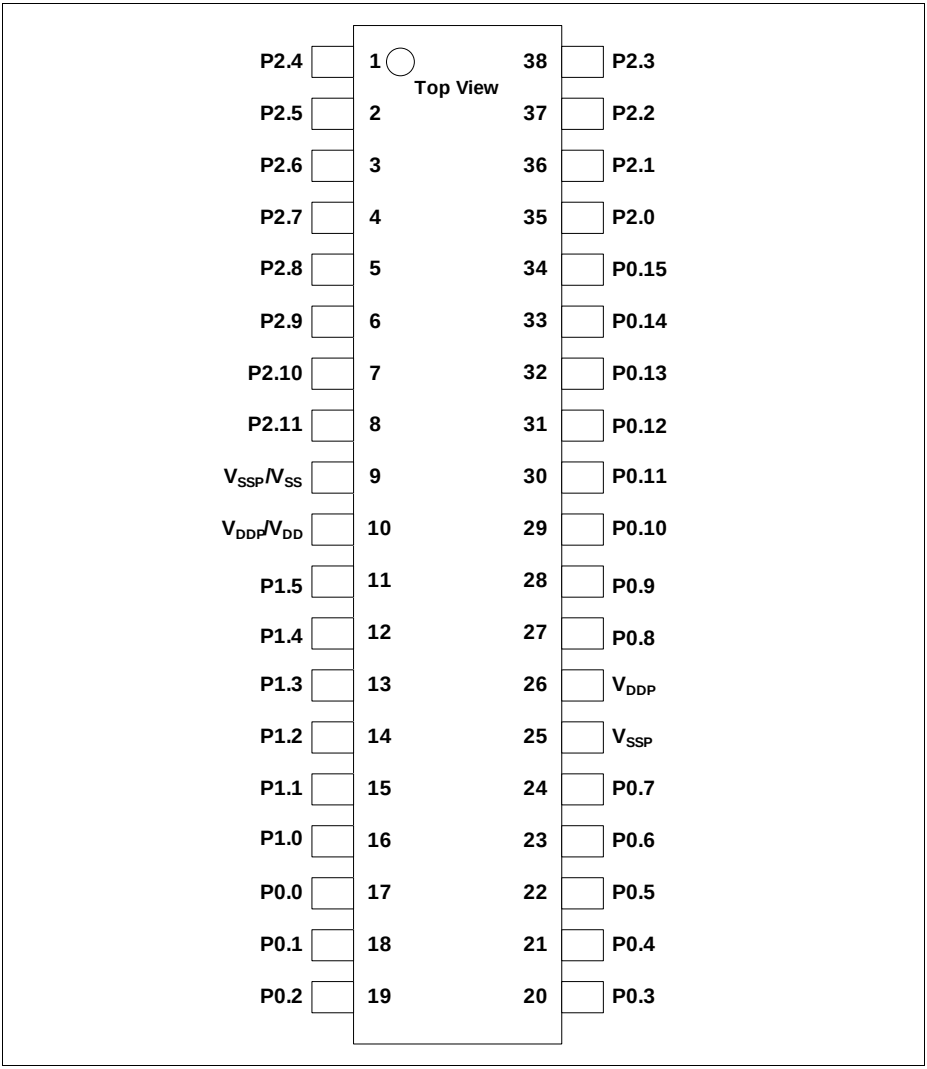


Figure 6 XMC1400 PG-TSSOP-38-9 Pin Configuration (top view)

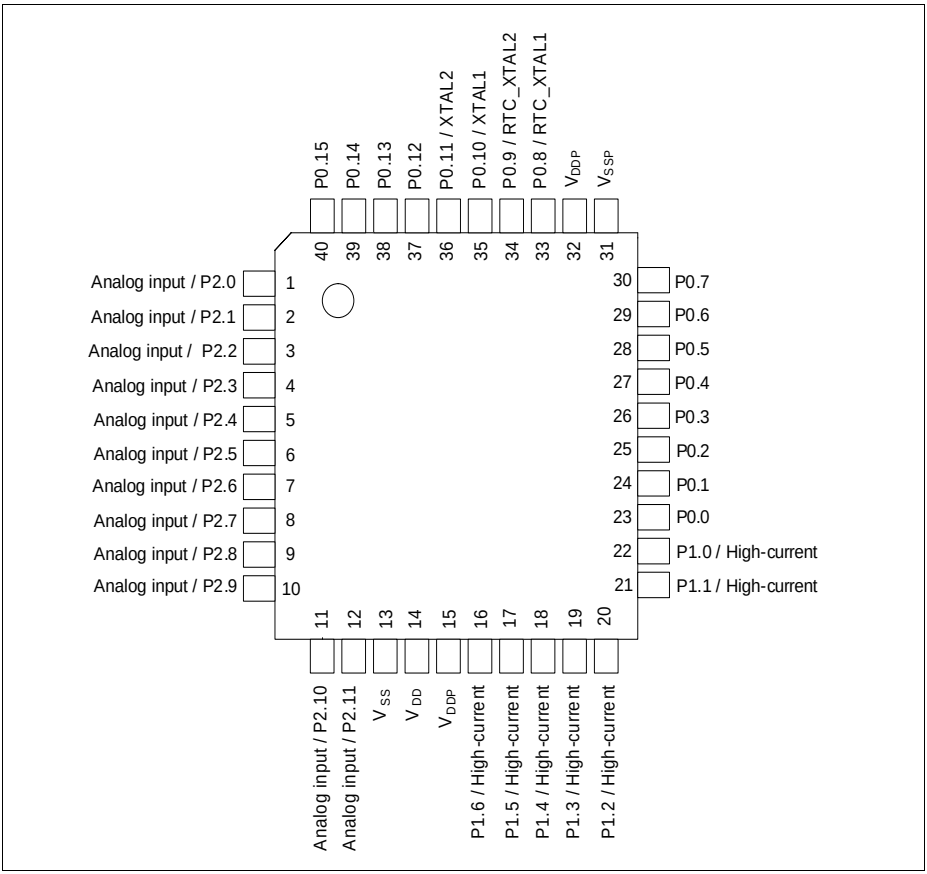


Figure 7 XMC1400 PG-VQFN-40-17 Pin Configuration (top view)

Table 9 Port I/O Functions (cont'd)

Function	Outputs									Inputs										
	ALT1	ALT2	ALT3	ALT4	ALT5	ALT6	ALT7	ALT8	ALT9	Input	Input	Input	Input	Input	Input	Input	Input	Input	Input	Input
P4.10		LEDTS2.LINE6	LEDTS2.COL1	LEDTS1.COL1	CCU80.OUT00	CCU40.OUT2	USIC1_CH0.SELO3	CCU81.OUT32	CCU81.OUT00	BCCU0.TRAPIND	CCU40.IN2AV	CCU41.IN2BA		CCU81.IN3AB			USIC1_CH0.DX2D	USIC1_CH1.DX5A			
P4.11		LEDTS2.LINE7	LEDTS2.COL0	LEDTS1.COL0	CCU80.OUT01	CCU40.OUT3	USIC1_CH0.SELO4	CCU81.OUT33	CCU81.OUT01		CCU40.IN3AV	CCU41.IN3BA					USIC1_CH0.DX2E	USIC1_CH1.DX3A	USIC1_CH1.DX4A		

Table 10 Hardware I/O Controlled Functions

Function	Outputs	Outputs	Inputs	Inputs	Pull Control	Pull Control	Pull Control	Pull Control
	HWO0	HWO1	HWI0	HWI1	HW0_PD	HW0_PU	HW1_PD	HW1_PU
P1.3		USIC0_CH0.DOUT3		USIC0_CH0.HWIN3	$\overline{\text{BCCU0.OUT5}}$	BCCU0.OUT5		
P1.4					$\overline{\text{BCCU0.OUT6}}$	BCCU0.OUT6		
P1.5					$\overline{\text{BCCU0.OUT7}}$	BCCU0.OUT7		
P1.6					$\overline{\text{BCCU0.OUT8}}$	BCCU0.OUT8		
P1.7								
P1.8								
P2.0					$\overline{\text{BCCU0.OUT1}}$	BCCU0.OUT1		
P2.1					$\overline{\text{BCCU0.OUT6}}$	BCCU0.OUT6		
P2.2					$\overline{\text{BCCU0.OUT0}}$	BCCU0.OUT0	$\overline{\text{CCU40.OUT3}}$	CCU40.OUT3
P2.3					$\overline{\text{ACMP2.OUT}}$	ACMP2.OUT		
P2.4					$\overline{\text{BCCU0.OUT8}}$	BCCU0.OUT8		
P2.5					$\overline{\text{ACMP1.OUT}}$	ACMP1.OUT		
P2.6					$\overline{\text{BCCU0.OUT2}}$	BCCU0.OUT2	$\overline{\text{CCU40.OUT3}}$	CCU40.OUT3
P2.7					$\overline{\text{BCCU0.OUT8}}$	BCCU0.OUT8	$\overline{\text{CCU40.OUT3}}$	CCU40.OUT3
P2.8					$\overline{\text{BCCU0.OUT1}}$	BCCU0.OUT1	$\overline{\text{CCU40.OUT2}}$	CCU40.OUT2
P2.9					$\overline{\text{BCCU0.OUT7}}$	BCCU0.OUT7	$\overline{\text{CCU40.OUT2}}$	CCU40.OUT2
P2.10					$\overline{\text{BCCU0.OUT4}}$	BCCU0.OUT4		
P2.11					$\overline{\text{BCCU0.OUT5}}$	BCCU0.OUT5		
P2.12					$\overline{\text{BCCU0.OUT3}}$	BCCU0.OUT3	$\overline{\text{CCU41.OUT0}}$	CCU41.OUT0
P2.13					$\overline{\text{BCCU0.OUT4}}$	BCCU0.OUT4	$\overline{\text{CCU41.OUT2}}$	CCU41.OUT2
P3.0								
P3.1		USIC1_CH0.DOUT3		USIC1_CH0.HWIN3				
P3.2		USIC1_CH0.DOUT2		USIC1_CH0.HWIN2				
P3.3		USIC1_CH0.DOUT1		USIC1_CH0.HWIN1				
P3.4		USIC1_CH0.DOUT0		USIC1_CH0.HWIN0				
P4.0								
P4.1								
P4.2								
P4.3								

Table 10 Hardware I/O Controlled Functions

Function	Outputs	Outputs	Inputs	Inputs	Pull Control	Pull Control	Pull Control	Pull Control
	HWO0	HWO1	HWI0	HWI1	HW0_PD	HW0_PU	HW1_PD	HW1_PU
P4.4	LEDTS2. EXTENDED0		LEDTS2.TSIN0	LEDTS2.TSIN0	Reserved for LEDTS Scheme A: pull-down disabled always	Reserved for LEDTS Scheme A: pull-down enabled always	Reserved for LEDTS Scheme B: pull-up enabled and pull-down disabled, and vice versa	
P4.5	LEDTS2. EXTENDED1		LEDTS2.TSIN1	LEDTS2.TSIN1				
P4.6	LEDTS2. EXTENDED2		LEDTS2.TSIN2	LEDTS2.TSIN2				
P4.7	LEDTS2. EXTENDED3		LEDTS2.TSIN3	LEDTS2.TSIN3				
P4.8	LEDTS2. EXTENDED4		LEDTS2.TSIN4	LEDTS2.TSIN4				
P4.9	LEDTS2. EXTENDED5		LEDTS2.TSIN5	LEDTS2.TSIN5				
P4.10	LEDTS2. EXTENDED6		LEDTS2.TSIN6	LEDTS2.TSIN6				
P4.11	LEDTS2. EXTENDED7		LEDTS2.TSIN7	LEDTS2.TSIN7				

3.1.2 Absolute Maximum Ratings

Stresses above the values listed under “Absolute Maximum Ratings” may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions may affect device reliability.

Table 11 Absolute Maximum Rating Parameters

Parameter	Symbol		Values			Unit	Note / Test Condition
			Min.	Typ.	Max.		
Junction temperature	T_J	SR	-40	–	115	°C	–
Storage temperature	T_{ST}	SR	-40	–	125	°C	–
Voltage on power supply pin with respect to V_{SSP}	V_{DDP}	SR	-0.3	–	6	V	–
Voltage on digital pins with respect to V_{SSP} [1]	V_{IN}	SR	-0.5	–	V_{DDP} + 0.5 or max. 6	V	whichever is lower
Voltage on P2 pins with respect to V_{SSP} [2]	V_{INP2}	SR	-0.3	–	V_{DDP} + 0.3	V	–
Voltage on analog input pins with respect to V_{SSP}	V_{AIN} V_{AREF}	SR	-0.5	–	V_{DDP} + 0.5 or max. 6	V	whichever is lower
Input current on any pin during overload condition	I_{IN}	SR	-10	–	10	mA	–
Absolute maximum sum of all input currents during overload condition	ΣI_{IN}	SR	-50	–	+50	mA	–

1) Excluding port pins P2.[1,2,6,7,8,9,11].

2) Applicable to port pins P2.[1,2,6,7,8,9,11].

Table 21 OSC_XTAL Parameters

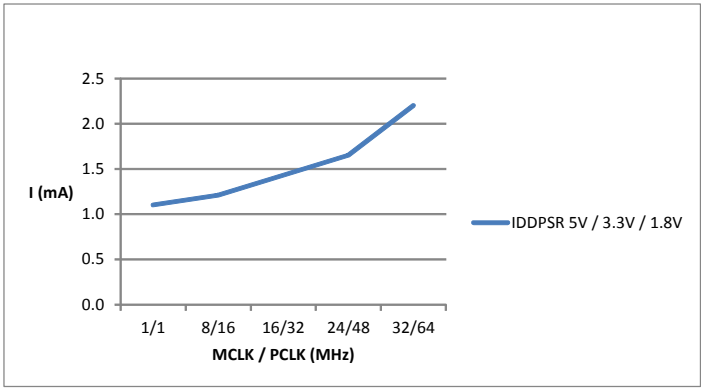
Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Input frequency	f_{OSC} SR	4	–	48	MHz	Direct Input Mode
		4	–	20	MHz	External Crystal Mode
Oscillator start-up time[1)2)]	t_{OSCS} CC	–	–	10	ms	
Input voltage at XTAL1	V_{IX} SR	-0.3	–	1.5	V	External Crystal Mode
		-0.3	–	5.5	V	Direct Input Mode
Input amplitude (peak-to-peak) at XTAL1[2)3)]	V_{PPX} SR	0.6	–	1.7	V	External Crystal Mode

1) t_{OSCS} is defined from the moment the oscillator is enabled wih SCU_ANAOSCHPCTRL.MODE until the oscillations reach an amplitude at XTAL1 of 0.9 * V_{PPX}.

2) The external oscillator circuitry must be optimized by the customer and checked for negative resistance and amplitude as recommended and specified by crystal suppliers.

3) If the shaper unit is enabled and not bypassed.

Figure 18 shows typical graphs for sleep mode current for V_{DDP} = 5 V, V_{DDP} = 3.3 V, V_{DDP} = 1.8 V across different clock frequencies.



Condition:
1. TA = +25° C

Figure 18 Sleep mode, peripherals clocks disabled, Flash powered down: Supply current I_{DDPSD} over supply voltage V_{DDP} for different clock frequencies

Table 24 provides the active current consumption of some modules operating at 5 V power supply at 25 °C. The typical values shown are used as a reference guide on the current consumption when these modules are enabled.

Table 24 Typical Active Current parameter table

Active Current Consumption	Symbol	Limit Values	Unit	Test Condition
		Typ.		
Baseload current	I_{CPUDDC}	4.14	mA	Modules including Core, SCU, PORT, memories, ANATOP[1)]
VADC and SHS	I_{ADCDDC}	3.73	mA	Set CGATCLR0.VADC to 1[2)]
USICx	$I_{USIC0DDC}$	1.35	mA	Set CGATCLR0.USIC0 to 1[3)]
CCU4x	$I_{CCU40DDC}$	0.99	mA	Set CGATCLR0.CCU40 to 1[4)]
CCU8x	$I_{CCU80DDC}$	1.00	mA	Set CGATCLR0.CCU80 to 1[5)]
POSIFx	$I_{PIF0DDC}$	1.05	mA	Set CGATCLR0.POSIF0 to 1[6)]
LEDTSx	$I_{LTSxDDC}$	1.14	mA	Set CGATCLR0.LEDTSx to 1[7)]
BCCU0	$I_{BCCU0DDC}$	0.29	mA	Set CGATCLR0.BCCU0 to 1[8)]
MATH	$I_{MATHDDC}$	0.50	mA	Set CGATCLR0.MATH to 1[9)]
WDT	I_{WDTDDC}	0.03	mA	Set CGATCLR0.WDT to 1[10)]
RTC	I_{RTCDDC}	0.01	mA	Set CGATCLR0.RTC to 1[11)]
MultiCAN	$I_{MCANDDC}$	1.38	mA	Set CGATCLR0.MCAN0 to 1[12)]

1) Baseload current is measured with device running in user mode, MCLK=PCLK=48 MHz, with an endless loop in the flash memory. The clock to the modules stated in CGATSTAT0 are gated.

2) Active current is measured with: module enabled, MCLK=48 MHz, running in auto-scan conversion mode

3) Active current is measured with: module enabled, each of the 2 USIC channels sending alternate messages at 57.6 kbaud every 200 ms

4) Active current is measured with: module enabled, MCLK=PCLK=48 MHz, 1 CCU4 slice for PWM switching at 20kHz with duty cycle varying at 10%-90%, 1 CCU4 slice in capture mode for reading period and duty cycle

5) Active current is measured with: module enabled, MCLK=PCLK=48 MHz, 3 CCU8 slices with PWM frequency at 20kHz and a period match interrupt used to toggle duty cycle between 10% and 90%

6) Active current is measured with: module enabled, MCLK=48 MHz, PCLK=96 MHz, hall sensor mode

7) Active current is measured with: module enabled, MCLK=48 MHz, 1 LED column, 6 LED/TS lines, Pad Scheme A with large pad hysteresis config, time slice duration = 1.048 ms

8) Active current is measured with: module enabled, MCLK=48 MHz, PCLK=96MHz, FCLK=0.8 MHz, Normal mode (BCCU clock = FCLK/4), 4 BCCU Channels with packers enabled and 1 Dimming Engine, change color or dim every 1s

9) Active current is measured with: module enabled, MCLK=48 MHz, PCLK=96 MHz, tangent calculation in while loop; CORDIC circular rotation, no keep, autostart; 32-by-32 bit signed DIV, autostart, DVS right shift by 11

3.3.2 Power-Up and Supply Threshold Characteristics

Table 26 provides the characteristics of the supply threshold in XMC1400.

The guard band between the lowest valid operating voltage and the brownout reset threshold provides a margin for noise immunity and hysteresis. The electrical parameters may be violated while V_{DDP} is outside its operating range.

The brownout detection triggers a reset within the defined range. The prewarning detection can be used to trigger an early warning and issue corrective and/or fail-safe actions in case of a critical supply voltage drop.

Note: These parameters are not subject to production test, but verified by design and/or characterization.

Table 26 Power-Up and Supply Threshold Parameters (Operating Conditions apply)

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
V_{DDP} ramp-up time	t_{RAMPUP} SR	V_{DDP}/ $S_{VDDPrise}$	–	10^7	µs	
V_{DDP} slew rate	S_{VDDPOP} SR	0	–	0.1	V/µs	Slope during normal operation
	S_{VDDP10} SR	0	–	10	V/µs	Slope during fast transient within +/-10% of V_{DDP}
	$S_{VDDPrise}$ SR	0	–	10	V/µs	Slope during power-on or restart after brownout event
	$S_{VDDPfall}$[1] SR	0	–	0.25	V/µs	Slope during supply falling out of the +/-10% limits[2]
V_{DDP} prewarning voltage	V_{DDPPW} CC	2.1	2.25	2.4	V	ANAVDEL.VDEL_SELECT = 00_B
		2.85	3	3.15	V	ANAVDEL.VDEL_SELECT = 01_B
		4.2	4.4	4.6	V	ANAVDEL.VDEL_SELECT = 10_B

3.3.5 SPD Timing Requirements

The optimum SPD decision time between 0_B and 1_B is 0.75 µs. With this value the system has maximum robustness against frequency deviations of the sampling clock on tool and on device side. However it is not always possible to exactly match this value with the given constraints for the sample clock. For instance for a oversampling rate of 4, the sample clock will be 8 MHz and in this case the closest possible effective decision time is 5.5 clock cycles (0.69 µs).

Table 30 Optimum Number of Sample Clocks for SPD

Sample Freq.	Sampling Factor	Sample Clocks 0_B	Sample Clocks 1_B	Effective Decision Time[1)]	Remark
8 MHz	4	1 to 5	6 to 12	0.69 µs	The other closest option (0.81 µs) for the effective decision time is less robust.

1) Nominal sample frequency period multiplied with 0.5 + (max. number of 0_B sample clocks)

For a balanced distribution of the timing robustness of SPD between tool and device, the timing requirements for the tool are:

- Frequency deviation of the sample clock is +/- 5%
- Effective decision time is between 0.69 µs and 0.75 µs (calculated with nominal sample frequency)

3.3.6 Peripheral Timings

Note: These parameters are not subject to production test, but verified by design and/or characterization.

3.3.6.1 Synchronous Serial Interface (USIC SSC) Timing

The following parameters are applicable for a USIC channel operated in SSC mode.

Note: Operating Conditions apply.

Table 31 USIC SSC Master Mode Timing

Parameter	Symbol		Values			Unit	Note / Test Condition
			Min.	Typ.	Max.		
SCLKOUT master clock period	t_{CLK}	CC	$4/MCLK$	–	–	ns	
Slave select output SELO active to first SCLKOUT transmit edge	t_1	CC	$t_{CLK}/2$ - 28	–	–	ns	
Slave select output SELO inactive after last SCLKOUT receive edge	t_2	CC	0	–	–	ns	
Data output DOUT[3:0] valid time	t_3	CC	-28	–	28	ns	
Receive data input DX0/DX[5:3] setup time to SCLKOUT receive edge	t_4	SR	75	–	–	ns	
Data input DX0/DX[5:3] hold time from SCLKOUT receive edge	t_5	SR	0	–	–	ns	

Table 32 USIC SSC Slave Mode Timing

Parameter	Symbol		Values			Unit	Note / Test Condition
			Min.	Typ.	Max.		
DX1 slave clock period	t_{CLK}	SR	$4/MCLK$	–	–	ns	
Select input DX2 setup to first clock input DX1 transmit edge[1)]	t_{10}	SR	16	–	–	ns	

Table 32 USIC SSC Slave Mode Timing

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Select input DX2 hold after last clock input DX1 receive edge[1]	t_{11} SR	17	–	–	ns	
Receive data input DX0/DX[5:3] setup time to shift clock receive edge[1]	t_{12} SR	21	–	–	ns	
Data input DX0/DX[5:3] hold time from clock input DX1 receive edge[1]	t_{13} SR	15	–	–	ns	
Data output DOUT[3:0] valid time	t_{14} CC	-	–	71	ns	

1) These input timings are valid for asynchronous input signal handling of slave select input, shift clock input, and receive data input (bits DXnCR.DSEN = 0).

3.3.6.2 Inter-IC (IIC) Interface Timing

The following parameters are applicable for a USIC channel operated in IIC mode.

Note: Operating Conditions apply.

Table 33 USIC IIC Standard Mode Timing[1)]

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Fall time of both SDA and SCL	t_1 CC/SR	-	-	300	ns	
Rise time of both SDA and SCL	t_2 CC/SR	-	-	1000	ns	
Data hold time	t_3 CC/SR	0	-	-	µs	
Data set-up time	t_4 CC/SR	250	-	-	ns	
LOW period of SCL clock	t_5 CC/SR	4.7	-	-	µs	
HIGH period of SCL clock	t_6 CC/SR	4.0	-	-	µs	
Hold time for (repeated) START condition	t_7 CC/SR	4.0	-	-	µs	
Set-up time for repeated START condition	t_8 CC/SR	4.7	-	-	µs	
Set-up time for STOP condition	t_9 CC/SR	4.0	-	-	µs	
Bus free time between a STOP and START condition	t_{10} CC/SR	4.7	-	-	µs	
Capacitive load for each bus line	C_b SR	-	-	400	pF	

1) Due to the wired-AND configuration of an IIC bus system, the port drivers of the SCL and SDA signal lines need to operate in open-drain mode. The high level on these lines must be held by an external pull-up device, approximalely 10 kOhm for operation at 100 kbit/s, approximately 2 kOhm for operation at 400 kbit/s.

Table 34 USIC IIC Fast Mode Timing[1)]

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Fall time of both SDA and SCL	t_1 CC/SR	20 + 0.1*C_b [2)]	-	300	ns	
Rise time of both SDA and SCL	t_2 CC/SR	20 + 0.1*C_b	-	300	ns	
Data hold time	t_3 CC/SR	0	-	-	µs	
Data set-up time	t_4 CC/SR	100	-	-	ns	
LOW period of SCL clock	t_5 CC/SR	1.3	-	-	µs	
HIGH period of SCL clock	t_6 CC/SR	0.6	-	-	µs	
Hold time for (repeated) START condition	t_7 CC/SR	0.6	-	-	µs	
Set-up time for repeated START condition	t_8 CC/SR	0.6	-	-	µs	
Set-up time for STOP condition	t_9 CC/SR	0.6	-	-	µs	
Bus free time between a STOP and START condition	t_{10} CC/SR	1.3	-	-	µs	
Capacitive load for each bus line	C_b SR	-	-	400	pF	

1) Due to the wired-AND configuration of an IIC bus system, the port drivers of the SCL and SDA signal lines need to operate in open-drain mode. The high level on these lines must be held by an external pull-up device, approximalely 10 kOhm for operation at 100 kbit/s, approximately 2 kOhm for operation at 400 kbit/s.

2) C_b refers to the total capacitance of one bus line in pF.

The difference between junction temperature and ambient temperature is determined by $\Delta T = (P_{INT} + P_{IOSTAT} + P_{IODYN}) \times R_{\Theta JA}$

The internal power consumption is defined as
$P_{INT} = V_{DDP} \times I_{DDP}$ (switching current and leakage current).

The static external power consumption caused by the output drivers is defined as
$P_{IOSTAT} = \Sigma((V_{DDP}-V_{OH}) \times I_{OH}) + \Sigma(V_{OL} \times I_{OL})$

The dynamic external power consumption caused by the output drivers (P_{IODYN}) depends on the capacitive load connected to the respective pins and their switching frequencies.

If the total power dissipation for a given system configuration exceeds the defined limit, countermeasures must be taken to ensure proper system operation:

- Reduce V_{DDP}, if possible in the system
- Reduce the system frequency
- Reduce the number of output pins
- Reduce the load on active output drivers

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